Nobuo Satoh

List of Publications by Year
in descending order

55	254	1039880 9	1125617 13
papers	citations	h-index	g-index

55	55	55	219
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Multi-Probe Atomic Force Microscopy Using Piezoelectric Cantilevers. Japanese Journal of Applied Physics, 2007, 46, 5543.	0.8	22
2	Nanoscale Investigation of Optical and Electrical Properties by Dynamic-Mode Atomic Force Microscopy Using a Piezoelectric Cantilever. Japanese Journal of Applied Physics, 2003, 42, 4878-4881.	0.8	21
3	Multi-Probe Atomic Force Microscopy with Optical Beam Deflection Method. Japanese Journal of Applied Physics, 2007, 46, 5636.	0.8	19
4	Nanoscale liquid droplet deposition using the ultrasmall aperture on a dynamic mode AFM tip. Nanotechnology, 2011, 22, 175301.	1.3	17
5	Investigation of the depletion layer by scanning capacitance force microscopy with Kelvin probe force microscopy. Japanese Journal of Applied Physics, 2016, 55, 08NB10.	0.8	16
6	Dynamic-mode AFM using the piezoelectric cantilever: investigations of local optical and electrical properties. Applied Surface Science, 2002, 188, 425-429.	3.1	13
7	Scanning near-field optical microscopy system based on frequency-modulation atomic force microscopy using a piezoelectric cantilever. Japanese Journal of Applied Physics, 2014, 53, 125201.	0.8	12
8	Observation of silicon carbide Schottky barrier diode under applied reverse bias using atomic force microscopy/Kelvin probe force microscopy/scanning capacitance force microscopy. Japanese Journal of Applied Physics, 2017, 56, 08LB05.	0.8	11
9	Near-field light detection by conservative and dissipative force modulation methods using a piezoelectric cantilever. Applied Physics Letters, 2010, 96, 233104.	1.5	9
10	Nanoscale investigation of the silicon carbide double-diffused MOSFET with scanning capacitance force microscopy. Japanese Journal of Applied Physics, 2018, 57, 08NB09.	0.8	9
11	Investigations of Nanoparticles by Scanning Near-Field Optical Microscopy Combined with Kelvin Probe Force Microscopy Using a Piezoelectric Cantilever. Japanese Journal of Applied Physics, 2004, 43, 4651-4654.	0.8	7
12	Cross-sectional observation in nanoscale for Si power MOSFET by atomic force microscopy/Kelvin probe force microscopy/scanning capacitance force microscopy. Japanese Journal of Applied Physics, 2019, 58, SIIA04.	0.8	7
13	A flyback converter using power MOSFET to achieve high frequency operation beyond 13.56 MHz. , 2015, , .		6
14	Energy Band Diagram near the Interface of Aluminum Oxide on p-Si Fabricated by Atomic Layer Deposition without/with Rapid Thermal Cycle Annealing Determined by Capacitanceâ€"Voltage Measurements. E-Journal of Surface Science and Nanotechnology, 2012, 10, 22-28.	0.1	5
15	Driven by complementary operation of SiC-MOSFET and SiC-JFET within isolated flyback converter circuit. Nonlinear Theory and Its Applications IEICE, 2018, 9, 337-343.	0.4	5
16	Embryoid bodies cultured in in vivo diffusion chambers show reduced tumorigenicity while retaining expression of F9 antigens. Experimental Cell Research, 1984, 153, 506-514.	1.2	4
17	Stress reduction and structural quality improvement due to In doping in GaAs/Si. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2000, 68, 166-170.	1.7	4
18	Optical and mechanical detection of near-field light by atomic force microscopy using a piezoelectric cantilever. Japanese Journal of Applied Physics, 2016, 55, 08NB04.	0.8	4

#	Article	IF	Citations
19	Evaluation of carrier concentration reduction in GaN-on-GaN wafers by Raman spectroscopy and Kelvin force microscopy. Japanese Journal of Applied Physics, 2017, 56, 08LB07.	0.8	4
20	Investigation of an n^{â˜’} layer in a silicon fast recovery diode under applied bias voltages using Kelvin probe force microscopy. Japanese Journal of Applied Physics, 2018, 57, 08NB11.	0.8	4
21	Nanoscale investigation of bulk heterojunction organic solar cell by scanning capacitance force microscopy. Japanese Journal of Applied Physics, 2018, 57, 08NB05.	0.8	4
22	Twin-probe Atomic Force Microscopy with Optical Beam Deflection using Vertically Incident Lasers by Two Beam Splitter. IEEJ Transactions on Sensors and Micromachines, 2015, 135, 135-141.	0.0	4
23	Non-resonant frequency components observed in a dynamic Atomic Force Microscope. Nonlinear Theory and Its Applications IEICE, 2017, 8, 118-128.	0.4	4
24	Surface Potential Measurement of Tris(8-hydroxyquinolinato)aluminum and Bis[N-(1-naphthyl)-N-phenyl]benzidine Thin Films Fabricated on Indiumâ€“Tin Oxide by Kelvin Probe Force Microscopy. Japanese Journal of Applied Physics, 2011, 50, 071601.	0.8	4
25	Surface Potential Measurement of Tris(8-hydroxyquinolinato)aluminum and Bis[N-(1-naphthyl)-N-phenyl]benzidine Thin Films Fabricated on Indiumâ€“Tin Oxide by Kelvin Probe Force Microscopy. Japanese Journal of Applied Physics, 2011, 50, 071601.	0.8	3
26	Surface Potential Investigation of Fullerene Derivative Film on Platinum Electrode under UV Irradiation by Kelvin Probe Force Microscopy Using a Piezoelectric Cantilever. E-Journal of Surface Science and Nanotechnology, 2015, 13, 102-106.	0.1	3
27	Surface Potential Measurement of Organic Multi-layered Films on Electrodes by Kelvin Probe Force Microscopy. IEICE Transactions on Electronics, 2015, E98.C, 91-97.	0.3	3
28	Development of atomic force microscopy combined with scanning electron microscopy for investigating electronic devices. AIP Advances, 2019, 9, .	0.6	3
29	DIFFUSION CHAMBER CULTURE OF A SINGLE EMBRYOID BODY FROM THE TESTICULAR TERATOMA OF STRAIN 129 MOUSE. Development Growth and Differentiation, 1977, 19, 249-255.	0.6	2
30	Surface potential measurement of organic thin film on metal electrodes by dynamic force microscopy using a piezoelectric cantilever. Journal of Applied Physics, 2011, 109, 114306.	1.1	2
31	Multi-Probe Atomic Force Microscopy Using Piezo-Resistive Cantilevers and Interaction between Probes. E-Journal of Surface Science and Nanotechnology, 2013, 11, 13-17.	0.1	2
32	Surface potential measurement of fullerene/copper phthalocyanine films on indium tin oxide electrode by Kelvin probe force microscopy. Japanese Journal of Applied Physics, 2014, 53, 05FY03.	0.8	2
33	Surface potential measurement of fullerene derivative/copper phthalocyanine on indium tin oxide electrode by Kelvin probe force microscopy. Japanese Journal of Applied Physics, 2015, 54, 08KF06.	0.8	2
34	Nanoscale observation of organic thin film by atomic force microscopy. Japanese Journal of Applied Physics, 2017, 56, 08LB08.	0.8	2
35	Characterization of Polycrystalline Solar Cell by Scanning Laser Magnetic Microscopy. IEEJ Transactions on Sensors and Micromachines, 2019, 139, 335-340.	0.0	2
36	Design of isolated class-Î¦₂ DC-DC converter based on harmonic analysis technology. , 2021, , .		2

#	Article	IF	Citations
37	Near-field light detection of a photo induced force by atomic force microscopy with frequency modulation. Japanese Journal of Applied Physics, 2017, 56, 08LB03.	0.8	1
38	Using dynamic force microscopy with piezoelectric cantilever for indentation and high-speed observation. Nonlinear Theory and Its Applications IEICE, 2017, 8, 98-106.	0.4	1
39	Surface potential measurement of n-type organic semiconductor thin films by mist deposition via Kelvin probe microscopy. Japanese Journal of Applied Physics, 2017, 56, 08LB04.	0.8	1
40	Development of evaluation system for solar cell by scanning with lens-focused white LED illumination. , 2018, , .		1
41	Evaluation of silicon carbide Schottky barrier diode within guard ring by multifunctional scanning probe microscopy. Japanese Journal of Applied Physics, 2020, 59, SN1014.	0.8	1
42	Observation of Power MOSFET Composed of Silicon Carbide with a Planar Type in the Voltage Applying State Using a Scanning Probe Microscope. IEEJ Transactions on Sensors and Micromachines, 2021, 141, 349-355.	0.0	1
43	Photo radiation pressure at resonance of frequency modulated micro cantilever. Nonlinear Theory and Its Applications IEICE, 2021, 12, 718-725.	0.4	1
44	Surface Potential and Topography Measurements of Gallium Nitride on Sapphire by Scanning Probe Microscopy. IEEJ Transactions on Sensors and Micromachines, 2016, 136, 96-101.	0.0	1
45	A Study on MHz Switching Operation in Flyback Converter for Lithium Ion Battery and its Parallelization. , 2020, , .		1
46	HESO: A Heterogeneous Energy Spreading Object - An Application of Power Packet Technology to Mobile Vehicle-. , 2020, , .		1
47	Design of Isolated Class-Î¦₂ DC-DC Converter Based on Harmonic Analysis Technology. IEEJ Transactions on Industry Applications, 2022, 142, 177-186.	0.1	1
48	Internal carotid artery aneurysm with prominent calcification: Report of a case. Oral Radiology, 1992, 8, 73-78.	0.9	0
49	Twinâ€Probe Atomic Force Microscopy with Optical Beam Deflection Using Vertically Incident Lasers by Two Beam Splitter. Electronics and Communications in Japan, 2016, 99, 92-100.	0.3	0
50	A flyback converter using power-MOSFETs to achieve high-frequency operation beyond 10MHz. , 2017, , .		0
51	Surface Potential Measurement of a Silicon Fast Recovery Diode under Applied Bias Voltages by Kelvin Probe Force Microscopy. , 2018, , .		0
52	Nanoscale investigation of power semiconductor devices by scanning capacitance force microscopy. , 2019, , .		0
53	Development of scanning capacitance force microscopy using the dissipative force modulation method. Measurement Science and Technology, 2020, 31, 035904.	1.4	0
54	Overview of Crystal for Power Devices. Journal of the Institute of Electrical Engineers of Japan, 2017, 137, 673-674.	0.0	0

#	Article	IF	Citations
55	Investigation of power semiconductor devices under applying voltage by multi-purpose scanning probe microscope. , 2020, , .		0